## Notice of References Cited Application/Control No. 09/896,166 Examiner Gregory J. Vaughn Applicant(s)/Patent Under Reexamination TISCHER, STEVEN NEIL Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,327,628 B1	12-2001	Anuff et al.	719/311
*	В	US-6,336,124 B1	01-2002	Alam et al.	715/523
*	С	US-6,477,549 B1	11-2002	Hishida et al.	715/513
*	D	US-2002/0041287 A1	04-2002	Engeldrum et al.	345/589
*	E	US-2002/0051080 A1	05-2002	Tanaka, Koichiro	348/552
*	F	US-2002/0080168 A1	06-2002	Hilliard et al.	345/744
*	G	US-2002/0091738 A1	07-2002	Rohrabaugh et al.	707/517
*	Н	US-2002/0135621 A1	09-2002	Angiulo et al.	345/838
*	1	US-2002/0161803 A1	10-2002	Shelton, Richard M.	707/528
*	J	US-2002/0165881 A1	11-2002	Shelton, Richard M.	707/526
	К	US-			
	L	US-			
	М	US-		-	

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	z					
	0					
	Ъ					
	Q			,		
	·R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	Х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.